


<b>Search Notes</b>  	<b>Application/Control No.</b>  10509203	<b>Applicant(s)/Patent Under Reexamination</b>  KITAMURA, TAKUYA
	<b>Examiner</b>  Yeh, Eueng-nan	<b>Art Unit</b>  2624

SEARCHED			
Class	Subclass	Date	Examiner
382	239	2008.06.20	ey
341	51	2008.06.20	ey
348	404.1-407.1, 419.1	2008.06.20	ey
358	426.02-426.11	2008.06.20	ey

SEARCH NOTES		
Search Notes	Date	Examiner
(382/239) text search - see search outputs	2007/11/28	ey
EAST search - see search outputs	2007/11/28	ey
PALM inventor search - see search output	2007/11/09	ey
PTO_PLUS_search - see search history outputs	2008.06.12	ey
update search - refer to search history outputs	2008.06.17	ey
Google Scholar search - refer to search history outputs	2008.06.20	ey
IEEE search - refer to search history outputs	2008.06.20	ey

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner
	PGPUB text search - Jun 17, 2008, see interference search printout	2008.06.17	ey